



CHENMKO ENTERPRISE CO.,LTD

Halogens free devices

**SURFACE MOUNT
General Purpose Transistor**

VOLTAGE 25 Volts CURRENT 200 mAmpere

CHT4124SGP

APPLICATION

- * AF input stages and driver applicationon equipment.
- * Other general purpose applications.

FEATURE

- * Small surface mounting type. (SC-88/SOT-363)
- * High current gain.
- * Suitable for high packing density.
- * Low collector-emitter saturation.
- * High saturation current capability.

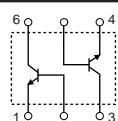
CONSTRUCTION

- * Two internal isolated NPN transistors in one package.

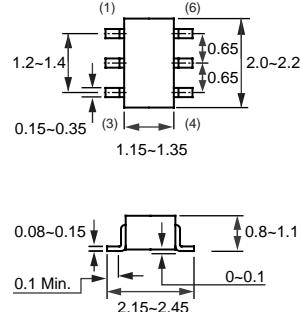
MARKING

- * CS

CIRCUIT



SC-88/SOT-363



Dimensions in millimeters

SC-88/SOT-363

LIMITING VALUES

In accordance with the Absolute Maximum Rating System (IEC 60134).

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{CBO}	collector-base voltage	open emitter	–	30	V
V_{CEO}	collector-emitter voltage	open base	–	25	V
V_{EBO}	emitter-base voltage	open collector	–	5	V
I_C	collector current (DC)		–	200	mA
P_{tot}	total power dissipation	$T_{amb} \leq 25^\circ\text{C}$; note 1	–	200	mW
T_{stg}	storage temperature		–65	+150	°C
T_j	junction temperature		–	150	°C
T_{amb}	operating ambient temperature		–65	+150	°C

Note

1. Transistor mounted on an FR4 printed-circuit board.

2004-11

RATING CHARACTERISTIC CURVES (CHT4124SGP)

CHARACTERISTICS

$T_{amb} = 25^{\circ}\text{C}$ unless otherwise specified.

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
$V_{(BR)CBO}$	collector-base breakdown voltage	$I_C = 10\mu\text{A}; I_E = 0\text{A}$	30	—	V
$V_{(BR)CEO}$	collector-emitter breakdown voltage	$I_C = 1\text{mA}; I_B = 0\text{A}$	25	—	V
$V_{(BR)EBO}$	emitter-base breakdown voltage	$I_E = 10\mu\text{A}; I_C = 0\text{A}$	5	—	V
I_{CBO}	collector cut-off current	$I_E = 0; V_{CB} = 20\text{ V}$	—	50	nA
I_{EBO}	emitter cut-off current	$I_C = 0; V_{EB} = 3\text{ V}$	—	50	nA
h_{FE}	DC current gain	$I_C = 50\text{ mA}; V_{CE} \neq 1\text{V};$ note 3	60	—	
h_{FE}	DC current gain	$I_C = 2\text{ mA}; V_{CE} = 1\text{V}$	120	360	
V_{CEsat}	collector-emitter saturation	$I_C = 50\text{ mA}; I_B = 5\text{ mA}$	—	300	mV
V_{BESat}	base-emitter saturation voltage	$I_C = 50\text{ mA}; I_B = 5\text{ mA}$	—	950	mV
C_{obo}	output capacitance	$I_E = i_e = 0; V_{CB} = 5\text{ V}; f = 1\text{ MHz}$	—	4	pF
C_{ibo}	input capacitance	$I_E = i_e = 0; V_{CB} = 5\text{ V}; f = 1\text{ MHz}$	—	8	pF
f_T	transition frequency	$I_C = 10\text{ mA}; V_{CE} = 20\text{ V}; f = 100\text{ MHz}$	300	—	MHz

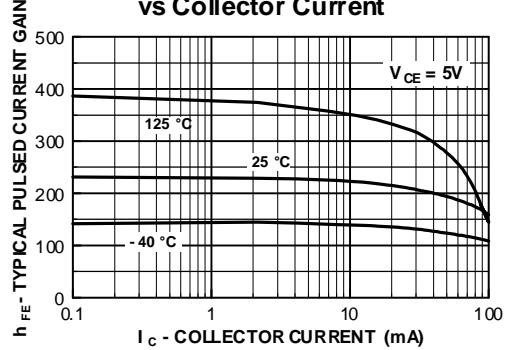
Note

3. Pulse test: $t_p \leq 300\text{ }\mu\text{s}; \delta \leq 0.02.$

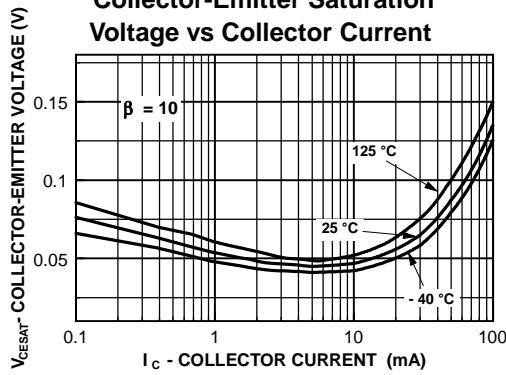
RATING CHARACTERISTIC CURVES (CHT4124SGP)

Typical Characteristics

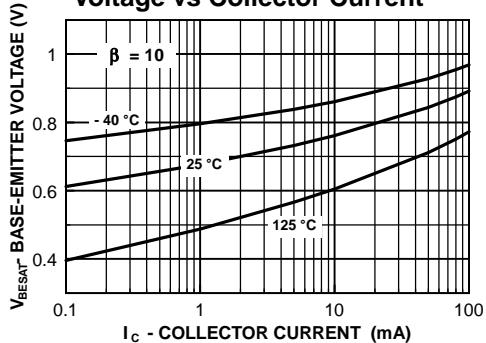
Typical Pulsed Current Gain vs Collector Current



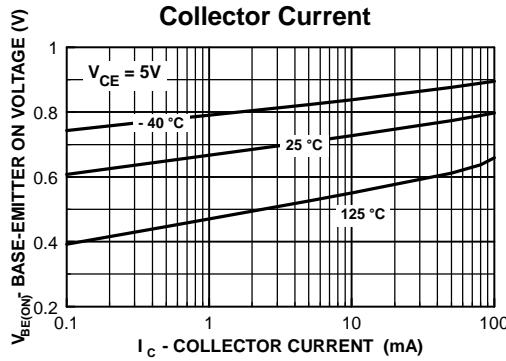
Collector-Emitter Saturation Voltage vs Collector Current



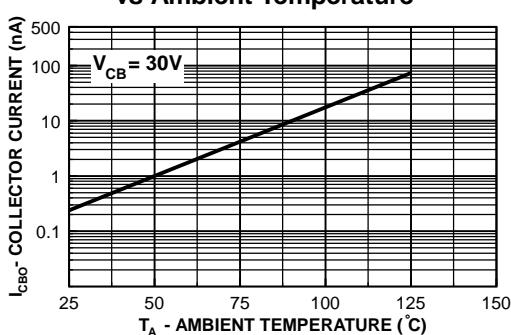
Base-Emitter Saturation Voltage vs Collector Current



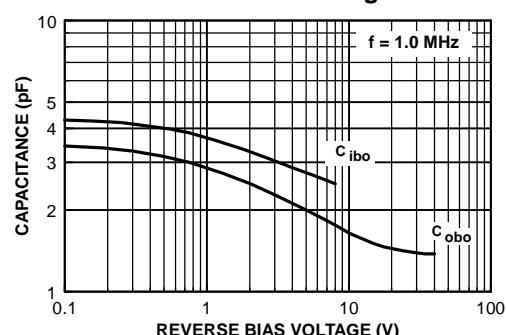
Base-Emitter ON Voltage vs Collector Current



Collector-Cutoff Current vs Ambient Temperature



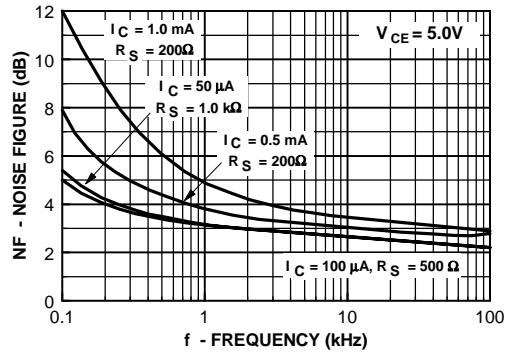
Capacitance vs Reverse Bias Voltage



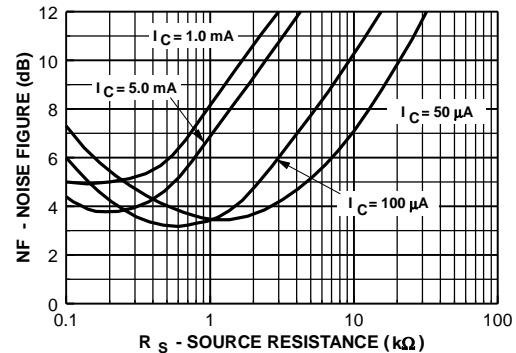
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Typical Characteristics

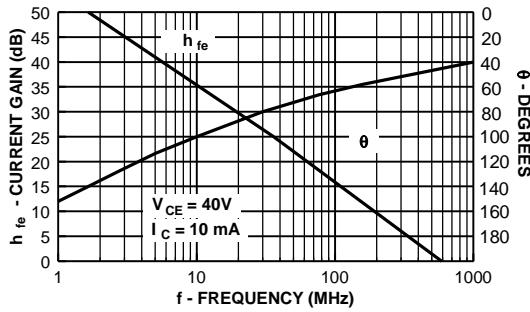
Noise Figure vs Frequency



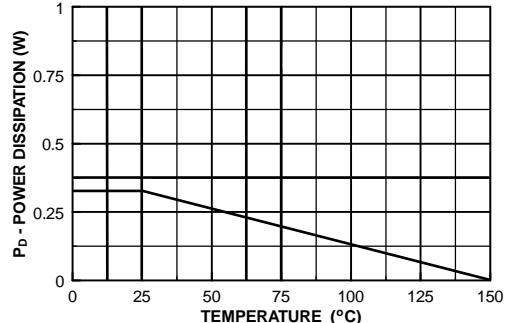
Noise Figure vs Source Resistance



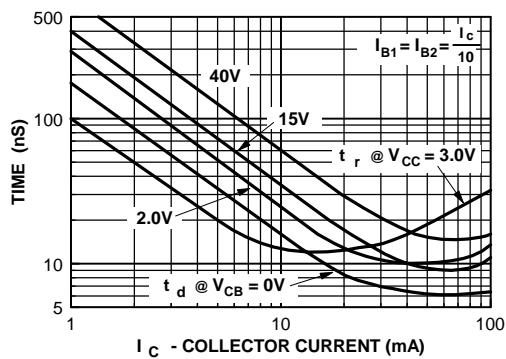
Current Gain and Phase Angle vs Frequency



Power Dissipation vs Ambient Temperature



Turn-On Time vs Collector Current



Rise Time vs Collector Current

